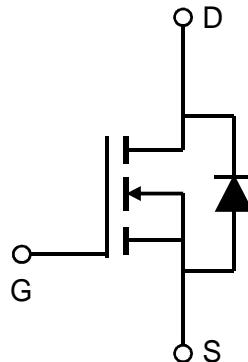


General Description

The AO4466 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. This device is suitable for use as a load switch or in PWM applications. The source leads are separated to allow a Kelvin connection to the source, which may be used to bypass the source inductance.



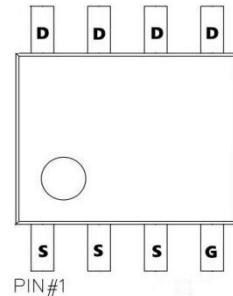
Product Summary

V_{DS} (V) = 30V

I_D = 10A

$R_{DS(ON)} < 18m\Omega$ ($V_{GS} = 10V$)

$R_{DS(ON)} < 25m\Omega$ ($V_{GS} = 4.5V$)



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|---|----------------|------------|-------|
| Drain-Source Voltage | V_{DS} | 30 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ^{AF} | I_D | 10 | A |
| $T_A=70^\circ C$ | | 7 | |
| Pulsed Drain Current ^B | I_{DM} | 64 | |
| Power Dissipation | P_D | 3.1 | W |
| $T_A=70^\circ C$ | | 2 | |
| Avalanche Current ^{B, G} | I_{AR} | 12 | A |
| Repetitive avalanche energy 0.1mH ^{B, G} | E_{AR} | 7 | mJ |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | °C |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 36 | 40 | °C/W |
| Steady-State | | 62 | 75 | °C/W |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 18 | 24 | °C/W |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|--------------------------|---------------------------------------|---|-----|------------------------|------|------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=250\mu\text{A}, V_{GS}=0\text{V}$ | 30 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=30\text{V}, V_{GS}=0\text{V}$ | | | 1 | μA |
| | | | | $T_J=55^\circ\text{C}$ | 5 | |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$ | | | 100 | nA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 1 | 1.5 | 2.5 | V |
| $I_{\text{D(ON)}}$ | On state drain current | $V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$ | 64 | | | A |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance | $V_{GS}=10\text{V}, I_D=10\text{A}$ | | 13 | 18 | $\text{m}\Omega$ |
| | | $V_{GS}=4.5\text{V}, I_D=5\text{A}$ | | 19 | 25 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=5\text{V}, I_D=3\text{A}$ | | 17 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=1\text{A}, V_{GS}=0\text{V}$ | | 0.75 | 1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | 2.4 | A |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$ | 298 | 373 | 448 | pF |
| C_{oss} | Output Capacitance | | 46 | 67 | 88 | pF |
| C_{rss} | Reverse Transfer Capacitance | | 24 | 41 | 58 | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$ | 0.6 | 1.8 | 2.8 | Ω |
| $Q_g(10\text{V})$ | Total Gate Charge | $V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=10\text{A}$ | 5.7 | 7.1 | 8.6 | nC |
| $Q_g(4.5\text{V})$ | Total Gate Charge | | 2.7 | 3.5 | 4.2 | nC |
| Q_{gs} | Gate Source Charge | | | 1.2 | | nC |
| Q_{gd} | Gate Drain Charge | | | 1.6 | | nC |
| $t_{\text{D(on)}}$ | Turn-On Delay Time | $V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$ | | 4.3 | | ns |
| t_r | Turn-On Rise Time | | | 2.8 | | ns |
| $t_{\text{D(off)}}$ | Turn-Off Delay Time | | | 15.8 | | ns |
| t_f | Turn-Off Fall Time | | | 3 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=10\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | 8.4 | 10.5 | 12.6 | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=10\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | 3.6 | 4.5 | 5.4 | nC |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$ | 4.7 | 6.0 | 7.2 | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$ | 5.3 | 6.6 | 8 | nC |

A: The value of R_{GJA} is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{GJA} is the sum of the thermal impedance from junction to lead R_{GJL} and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

F. The current rating is based on the $t \leq 10\text{s}$ junction to ambient thermal resistance rating.

G: $L=100\mu\text{H}, V_{DD}=0\text{V}, R_G=0\Omega$, rated $V_{DS}=30\text{V}$ and $V_{GS}=10\text{V}$

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

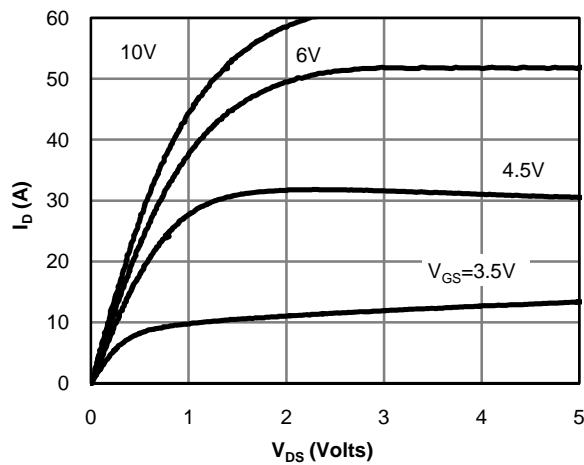


Fig 1: On-Region Characteristics

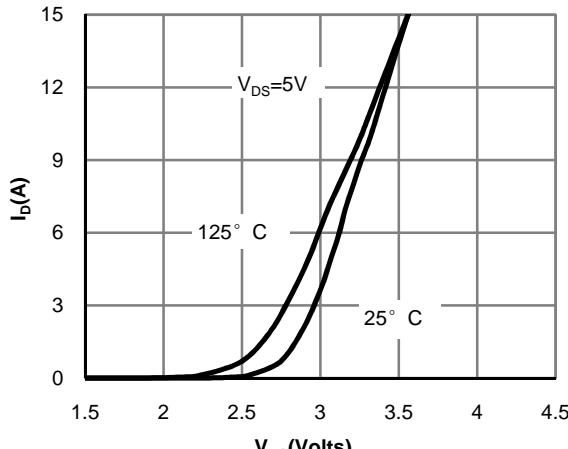


Figure 2: Transfer Characteristics

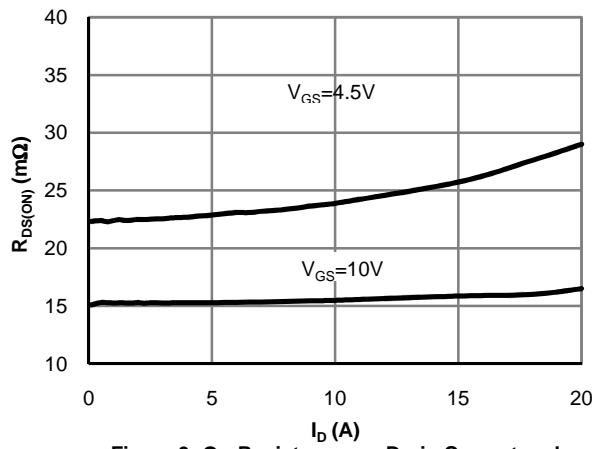


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

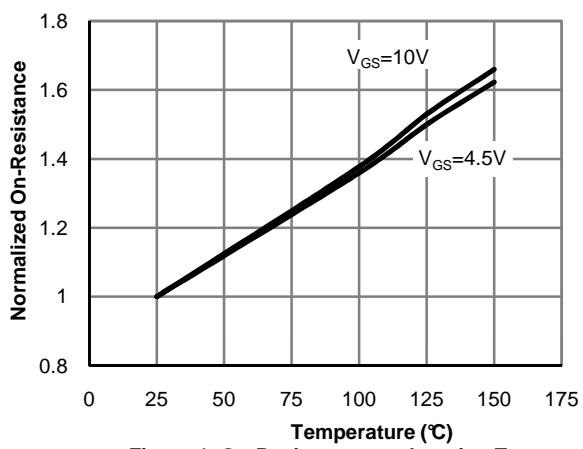


Figure 4: On-Resistance vs. Junction Temperature

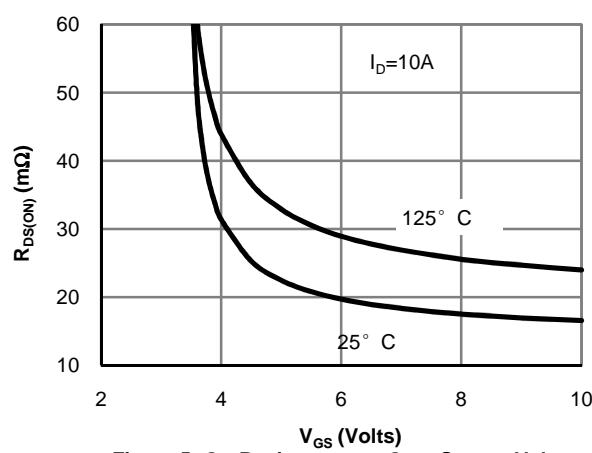


Figure 5: On-Resistance vs. Gate-Source Voltage

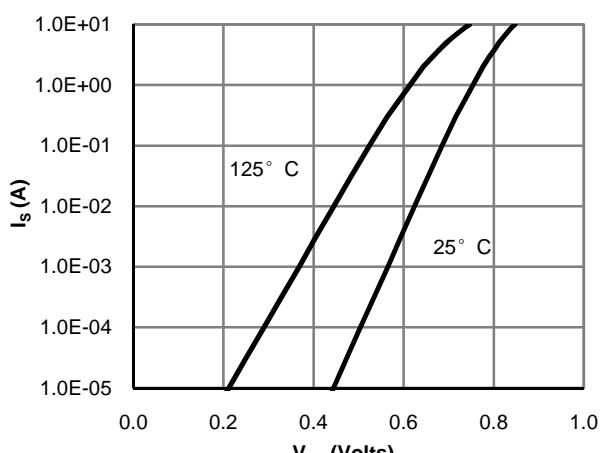


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

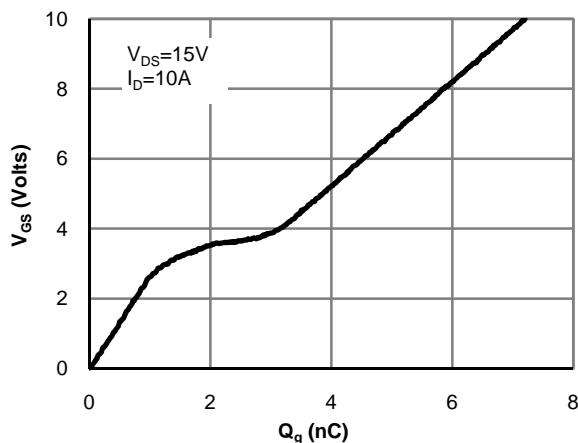


Figure 7: Gate-Charge Characteristics

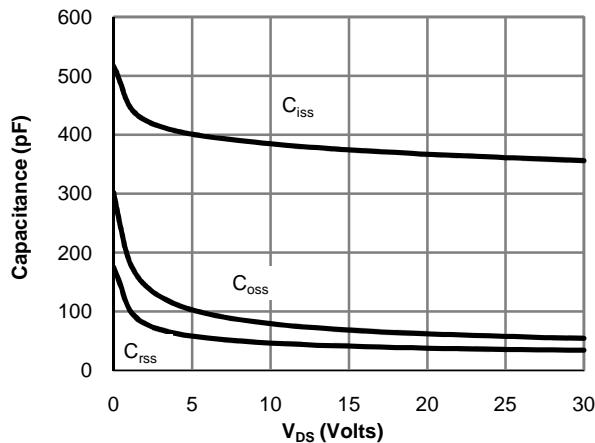


Figure 8: Capacitance Characteristics

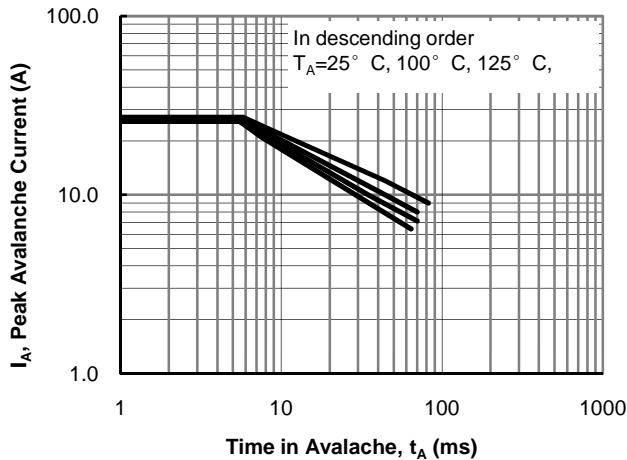


Figure 9: Single Pulse Avalanche Capability

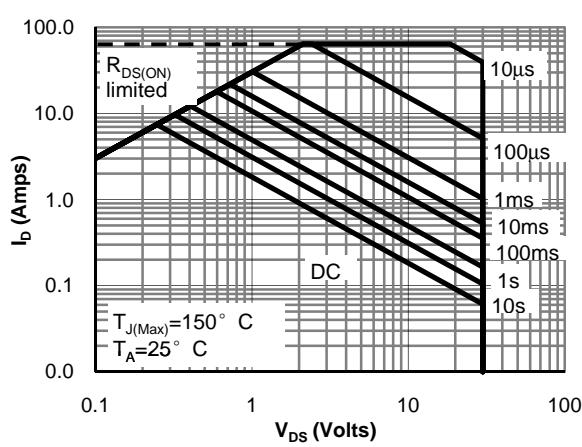


Figure 10: Maximum Forward Biased Safe Operating Area (Note E)

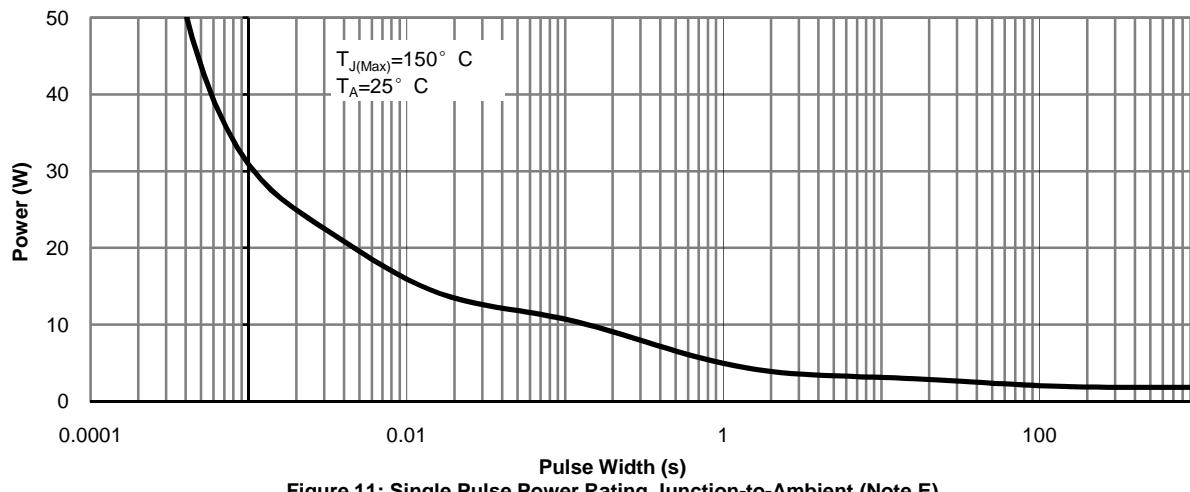


Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

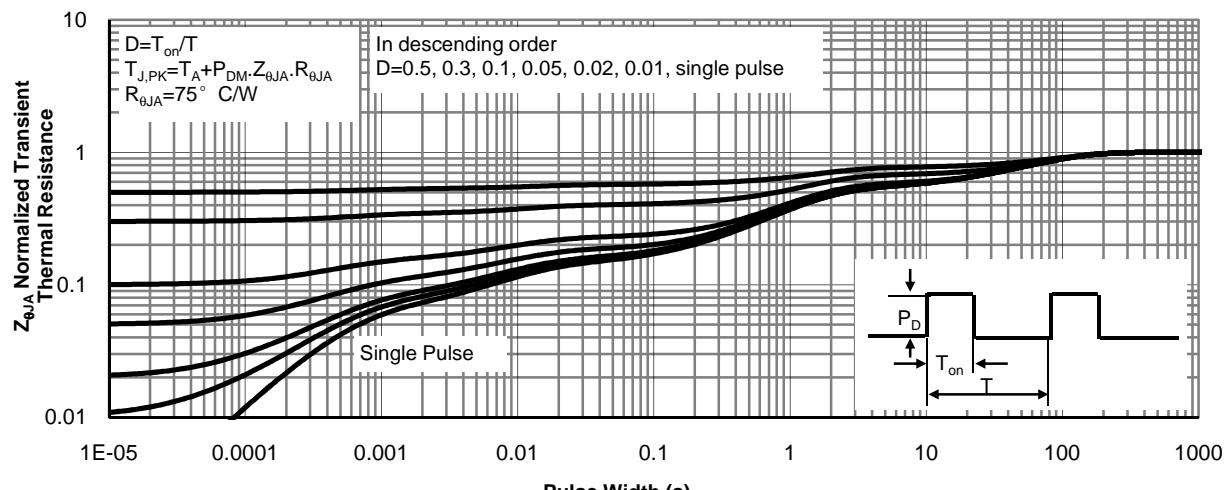
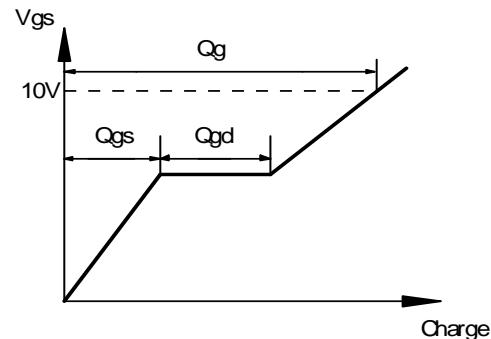
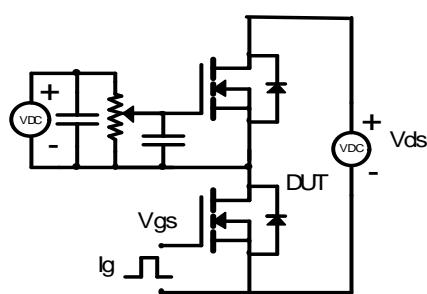
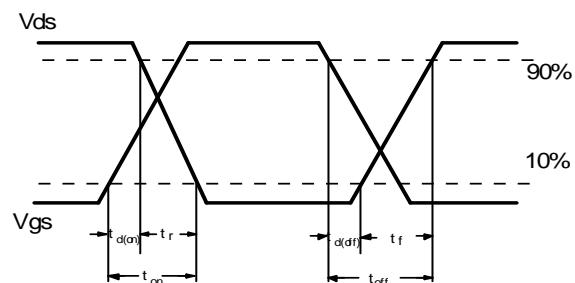
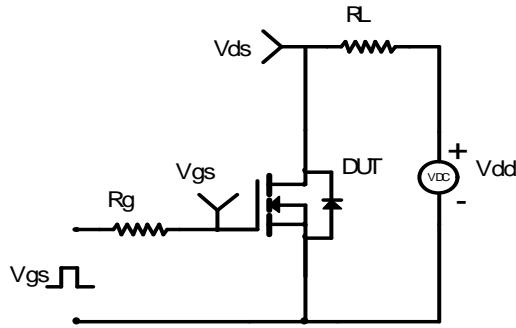


Figure 12: Normalized Maximum Transient Thermal Impedance

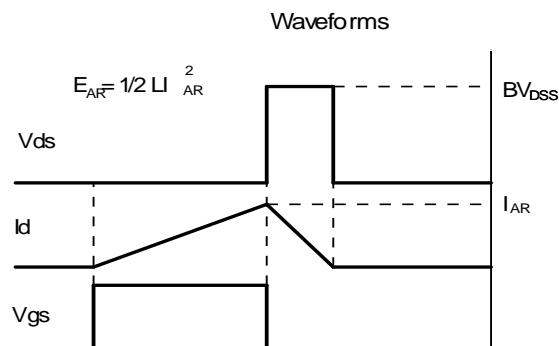
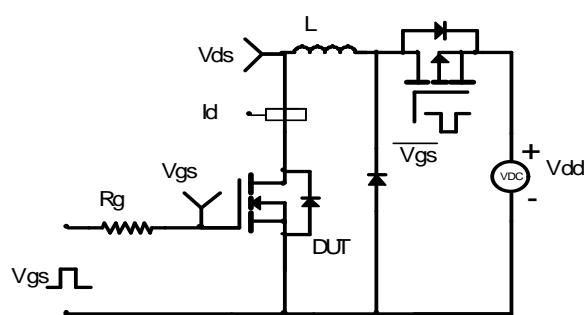
Gate Charge Test Circuit & Waveform



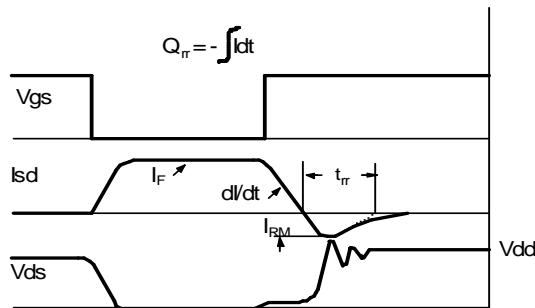
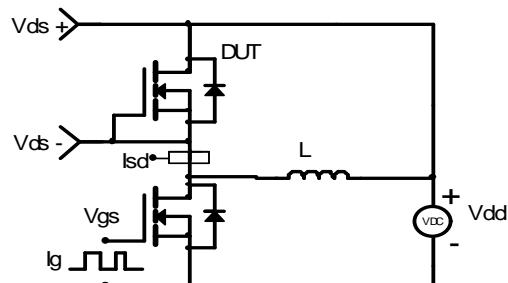
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit &

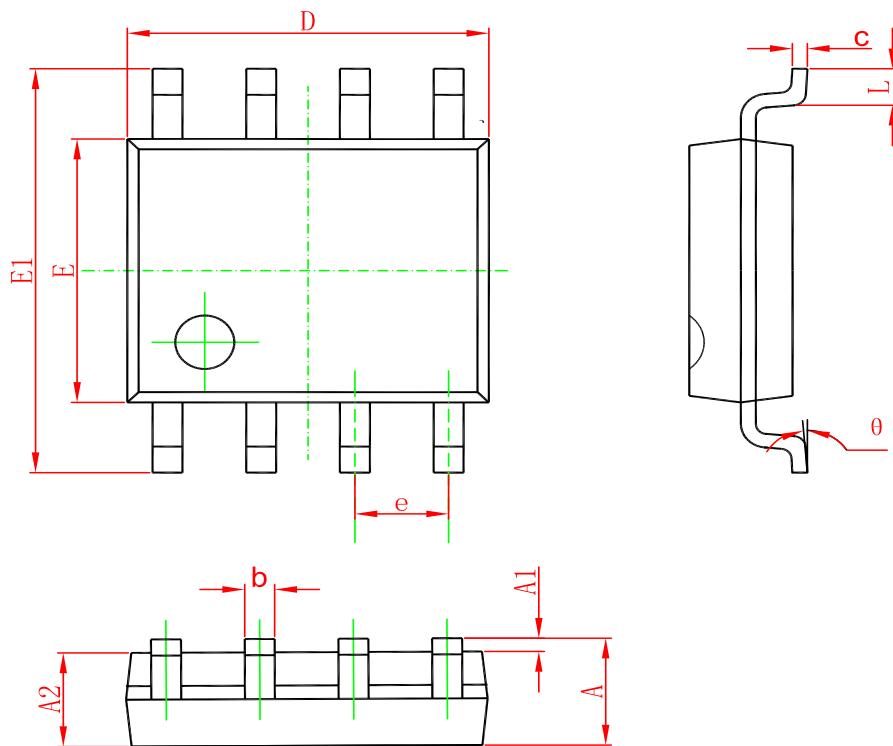


Diode Recovery Test Circuit & Waveforms



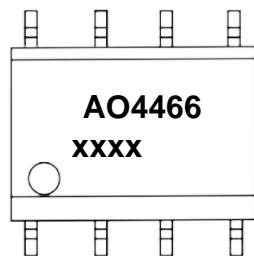
PACKAGE OUTLINE DIMENSIONS

SOP-8



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| A | 1.350 | 1.750 | 0.053 | 0.069 |
| A1 | 0.100 | 0.250 | 0.004 | 0.010 |
| A2 | 1.350 | 1.550 | 0.053 | 0.061 |
| b | 0.330 | 0.510 | 0.013 | 0.020 |
| c | 0.170 | 0.250 | 0.006 | 0.010 |
| D | 4.700 | 5.100 | 0.185 | 0.200 |
| E | 3.800 | 4.000 | 0.150 | 0.157 |
| E1 | 5.800 | 6.200 | 0.228 | 0.244 |
| e | 1.270(BSC) | | 0.050(BSC) | |
| L | 0.400 | 1.270 | 0.016 | 0.050 |
| θ | 0° | 8° | 0° | 8° |

Marking



("xxxx"代表年份周期)

Ordering information

| Order code | Package | Baseqty | Deliverymode |
|------------|---------|---------|---------------|
| AO4466 | SOP-8 | 3000 | Tape and reel |